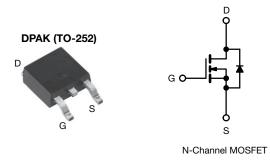
Vishay Siliconix



E Series Power MOSFET



PRODUCT SUMMARY					
V _{DS} (V) at T _J max.	650				
R _{DS(on)} typ. (Ω) at 25 °C	$V_{GS} = 10 V$	1.3			
Q _g max. (nC)	7.5				
Q _{gs} (nC)	1				
Q _{gd} (nC)	3				
Configuration	Single				

FEATURES

- 4th generation E series technology
- Low figure-of-merit (FOM) Ron x Qg
- Low effective capacitance (C_{o(er)})
- Reduced switching and conduction losses
- Avalanche energy rated (UIS)
- Material categorization: for definitions of compliance please see <u>www.vishay.com/doc?99912</u>

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial
 - Welding
 - Induction heating
 - Motor drives
 - Battery chargers
 - Solar (PV inverters)

ORDERING INFORMATION	
Package	DPAK (TO-252)
Lead (Pb)-free and halogen-free	SiHD1K4N60E-GE3

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-source voltage			V _{DS}	600	v	
Gate-source voltage			V _{GS}	± 30	v	
Continuous drain current (T _J = 150 °C)	V _{GS} at 10 V	$T_{C} = 25 \text{ °C}$ $T_{C} = 100 \text{ °C}$	L_	4.2		
	VGS at TO V	T _C = 100 °C	I _D	2.6	А	
Pulsed drain current ^a			I _{DM}	5		
Linear derating factor				0.5	W/°C	
Single pulse avalanche energy ^b			E _{AS}	14	mJ	
Maximum power dissipation			PD	63	W	
Operating junction and storage temperature ra	ange		T _J , T _{stg}	-55 to +150	°C	
Drain-source voltage slope		T _J = 125 °C	°C 70		1//	
Reverse diode dv/dt ^d		dv/dt		3	V/ns	
Soldering recommendations (peak temperatur	re) ^c	For 10 s		260	°C	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature
- b. V_{DD} = 140 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 1 A
- c. 1.6 mm from case
- d. $I_{SD} \leq I_D, \, di/dt$ = 100 A/µs, starting T_J = 25 $^\circ C$



COMPLIANT

HALOGEN

FREE



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$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	THERMAL RESISTANCE RAT	INGS							
Maximum junction-to-case (drain) R_{hulc} - 2.0 SPECIFICATIONS ($T_J = 25 °C$, unless otherwise noted) PARAMETER SYMBOL TEST CONDITIONS Min. TYP. MAX. UNI Static Drain-source breakdown voltage V_{DS} $V_{GS} = 0 V, I_D = 250 \mu A$ 600 - - V/V Gate-source breakdown voltage V_{DS} $V_{DS} = 120 \mu A$ 3.0 - 5.0 V/V Gate-source threshold voltage (N) $V_{OS} = 10 V$ $V_{DS} = 230 \mu A$ 3.0 - t 100 nA Cose = 430 V - t 100 $N_{OS} = \pm 20 V$ - t 100 nA Cose = 430 V V_{OS} = 480 V, V_{OS} = 0 V t t 100 nA t tA Drain-source on-state resistance $R_{DS(m)}$ $V_{OS} = 100 V$ $t_{OS} = 0 V$ $t_{OS} = 0 V$ $t_{OS} = 10 V$ $t_{OS} = 0 V$ $t_{OS} = 0 V$ $t_{OS} = 10 V$ $t_{OS} = 0 V$ $t_{OS} = 0 V$ $t_{OS} = 0 V$ $t_{OS} = 0 V$	PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum junction-to-case (drain) R_{Hulc} - 2.0 SPECIFICATIONS (T _J = 25 °C, unless otherwise noted) PARAMETER SYMBOL TEST CONDITIONS Min. TYP. MAX. UNI Static Diain-source breakdown voltage V_{DS} $V_{GS} = 0.V, I_D = 250 \mu A$ 600 - - V/V Gate-source breakdown voltage V_{DS} Reference to 25 °C, I_D = 1 mA - 0.68 - V/VC Gate-source breakdown voltage V_{DS} VGS = 250 µA 3.0 - - + 100 nA Gate-source leakage I_{QSS} $V_{DS} = 480 V, V_{QS} = 0 V$ - - + 101 nA Zero gate voltage drain current I_{DSS} $V_{DS} = 480 V, V_{QS} = 0 V, T_J = 125 °C - 10 µA Drain-source on-state resistance R_{DS(m)} V_{DS} = 400 V, I_D = 2.0 A - 0.8 - S Dynamic Input capacitance C_{cas} V_{DS} = 100 V, I_D = 2.0 A - 10 20 Reverse$	Maximum junction-to-ambient	R _{thJA}	- 62			*CAN			
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum junction-to-case (drain)	R _{thJC}	- 2.0				°C/W		
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$									
Static Vois Vois Vois Cois Vois Cois Vois Cois Cois <thcois< th=""> Cois Cois <</thcois<>	SPECIFICATIONS (T _J = 25 $^{\circ}$ C, u	unless otherwi	se noted)						
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
	Static	•				•	•	•	
	Drain-source breakdown voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 2	250 µA	600	-	-	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	V _{DS} temperature coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	, I _D = 1 mA	-	0.68	-	V/°C
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-source threshold voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 2	250 µA	3.0	-	5.0	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-source leakage					-	-	± 100	nA
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$		IGSS				-	-	± 1	μA
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Zero gate voltage drain current	1				-	-	1	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		IDSS	V _{DS} = 480 V	, V _{GS} = 0 V	/, T _J = 125 °C	-	-	10	μΑ
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-source on-state resistance	R _{DS(on)}	V _{GS} = 10 V	١ _c	₀ = 0.5 A	-	1.3	1.45	Ω
$ \begin{array}{c c c c c c c c c } \hline \begin{tabular}{ c c c c c c c } \hline \begin{tabular}{ c c c c c c c } \hline \begin{tabular}{ c c c c c c c } \hline \begin{tabular}{ c c c c c c c } \hline \begin{tabular}{ c c c c c c } \hline \begin{tabular}{ c c c c c } \hline \begin{tabular}{ c c c c c c } \hline \begin{tabular}{ c c c c c c c } \hline \begin{tabular}{ c c c c c c c } \hline \begin{tabular}{ c c c c c c c } \hline \begin{tabular}{ c c c c c c c c } \hline \begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	Forward transconductance a		V _{DS} =	= 20 V, I _D =	= 2.0 A	-	0.8	-	S
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Dynamic					•	•	•	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Input capacitance	C _{iss}	V _{DS} = 100 V,		-	172	-	pF	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Output capacitance	C _{oss}			-	19	-		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse transfer capacitance				-	4	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Effective output capacitance, energy related ^a	C _{o(er)}	V_{DS} = 0 V to 480 V, V_{GS} = 0 V		-	12	-		
Gate-source charge Q_{gs} $V_{GS} = 10 \text{ V}$ $I_D = 2.0 \text{ A}, V_{DS} = 480 \text{ V}$ $ 1$ $ nC$ Gate-drain charge Q_{gd} Q_{gd} $U_D = 2.0 \text{ A}, V_{DS} = 480 \text{ V}$ $ 1$ $ nC$ Turn-on delay time $t_{d(on)}$ $V_{DD} = 480 \text{ V}, I_D = 2.0 \text{ A}, V_{GS} = 10 \text{ V}$ $ 10$ 20 $ 10$ 20 Rise time t_r $V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$ $ 10$ 20 $ 22$ 44 Gate input resistance R_g $f = 1 \text{ MHz}, \text{ open drain}$ 2.1 4.2 8.4 Ω Drain-Source Body Diode CharacteristicsContinuous source-drain diode current I_S MOSFET symbol showing the integral reverse $p - n$ junction diode $ 4$ A Diode forward voltage V_{SD} $T_J = 25 \text{ °C}, I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}$ $ 1.2$ V Reverse recovery time t_{rr} $T_J = 25 \text{ °C}, I_F = I_S = 0.5 \text{ A}, di/dt = 100 \text{ A/µs}, V_R = 25 \text{ V}$ $ 2.22$ 444 ns	Effective output capacitance, time related ^b	C _{o(tr)}			-	50	-		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Total gate charge	Qg				-	5	7.5	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-source charge	Q _{gs}	V _{GS} = 10 V I _D = 2.0 A, V _{DS} = 480 V		-	1	-	nC	
Rise timetrVDD = 480 V, ID = 2.0 A, VGS = 10 V, Rg = 9.1 Ω -2346nsTurn-off delay timetd(off)Fall timetfGate input resistanceRgf = 1 MHz, open drain2.14.28.4 Ω Drain-Source Body Diode CharacteristicsContinuous source-drain diode currentIsMOSFET symbol showing the integral reverse p - n junction diode4ADiode forward currentIsMOSFET symbol showing the integral reverse p - n junction diode5ADiode forward voltageVsDTJ = 25 °C, Is = 0.5 A, VGS = 0 V1.2VReverse recovery timetrrTJ = 25 °C, IF = IS = 0.5 A, di/dt = 100 A/µs, VR = 25 V-0.81.6µC	Gate-drain charge					-	3	-	1
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Turn-on delay time	t _{d(on)}	V _{DD} = 480 V. I _D = 2.0 A.		-	10	20		
Turn-off delay time $t_{d(off)}$ $V_{GS} = 10 \ V, R_g = 9.1 \Omega$ -1020Fall time t_f -2244Gate input resistance R_g $f = 1 \ MHz$, open drain2.14.28.4 Ω Drain-Source Body Diode CharacteristicsContinuous source-drain diode current I_S MOSFET symbol showing the integral reverse $p - n$ junction diode4ADiode forward voltage V_{SD} $T_J = 25 \ ^\circ$ C, $I_S = 0.5 \ A$, $V_{GS} = 0 \ V$ 1.2VReverse recovery time t_{rr} $T_J = 25 \ ^\circ$ C, $I_F = I_S = 0.5 \ A$, di/dt = 100 A/µs, $V_R = 25 \ V$ 0.81.6µC	Rise time				-	23	46	1	
Fall time t_f -2244Gate input resistance R_g $f = 1 \text{ MHz}$, open drain2.14.28.4 Ω Drain-Source Body Diode CharacteristicsContinuous source-drain diode current I_S MOSFET symbol showing the integral reverse $p - n$ junction diode4APulsed diode forward current I_{SM} $MOSFET symbol$ showing the integral reverse $p - n$ junction diode4ADiode forward voltage V_{SD} $T_J = 25 \ ^\circ C$, $I_S = 0.5 \ ^\circ A$, $V_{GS} = 0 \ ^\circ$ 1.2 V Reverse recovery time t_{rr} $T_J = 25 \ ^\circ C$, $I_F = I_S = 0.5 \ ^\circ A$, di/dt = 100 A/µs, $V_R = 25 \ ^\circ A$ -0.81.6µC	Turn-off delay time	t _{d(off)}	V _{GS} =			-	10	20	ns
Drain-Source Body Diode CharacteristicsContinuous source-drain diode currentIsMOSFET symbol showing the integral reverse $p - n$ junction diode4Pulsed diode forward currentIsMIsM $r = 1, 25, 0, 1,$	Fall time				-	22	44	1	
Drain-Source Body Diode CharacteristicsContinuous source-drain diode currentIsMOSFET symbol showing the integral reverse $p - n$ junction diode4Pulsed diode forward currentIsMIsM $r = 1, 25, 0, 1,$	Gate input resistance	R _g	f = 1 MHz, open drain		2.1	4.2	8.4	Ω	
Continuous source-drain diode currentisshowing the integral reverse p - n junction diode4APulsed diode forward currentIsIs r_{SM} p - n junction diode5Diode forward voltageVspTJ = 25 °C, Is = 0.5 A, Vgs = 0 V1.2VReverse recovery time t_{rr} TJ = 25 °C, Is = 0.5 A, di/dt = 100 A/µs, Vg = 25 V1.6µC	Drain-Source Body Diode Characteristi		•					•	
Pulsed diode forward currentIIntegral foreign $ring (a + 0) = 000$ $ring (a + 0) $	Continuous source-drain diode current	۱ _S	showing the integral reverse		-	-	4		
Reverse recovery time t_{rr} $T_J = 25 \text{ °C}, I_F = I_S = 0.5 \text{ A},$ - 222 444 ns Reverse recovery charge Q_{rr} $di/dt = 100 \text{ A/}\mu\text{s}, V_R = 25 \text{ V}$ - 0.8 1.6 μC	Pulsed diode forward current	I _{SM}			-	-	5	A	
Reverse recovery time t_{rr} $T_J = 25 \text{ °C}, I_F = I_S = 0.5 \text{ A},$ - 222 444 ns Reverse recovery charge Q_{rr} $di/dt = 100 \text{ A/}\mu\text{s}, V_R = 25 \text{ V}$ - 0.8 1.6 μC	Diode forward voltage	V _{SD}	T _J = 25 °C, I _S = 0.5 A, V _{GS} = 0 V			-	-	1.2	V
Reverse recovery charge Q_{rr} $T_J = 25 \text{ °C}, I_F = I_S = 0.5 \text{ Å},$ - 0.8 1.6 μC di/dt = 100 A/µs, $V_R = 25 V$ - 0.8 1.6 μC	Reverse recovery time		T _J = 25 °C, I _F = I _S = 0.5 A,		-	222	444	ns	
	Reverse recovery charge				-	0.8	1.6	μC	
	Reverse recovery current				-	5.6	-	-	

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS}

b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS}



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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

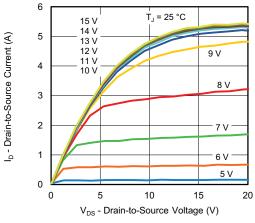


Fig. 1 - Typical Output Characteristics

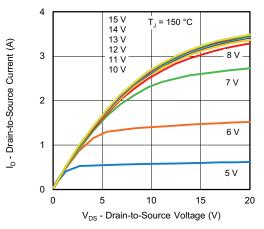


Fig. 2 - Typical Output Characteristics

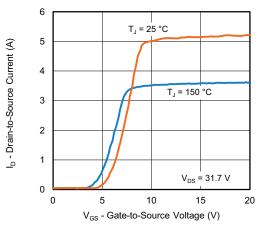


Fig. 3 - Typical Transfer Characteristics

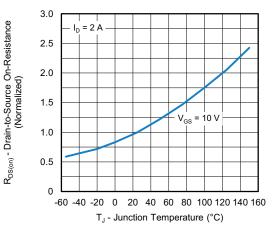


Fig. 4 - Normalized On-Resistance vs. Temperature

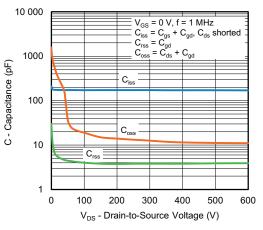
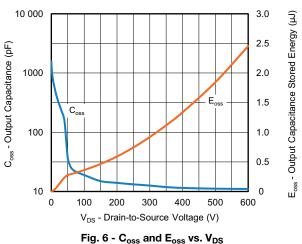


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



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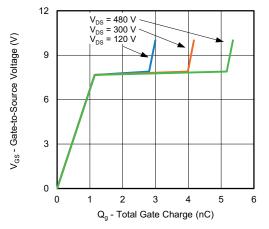


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

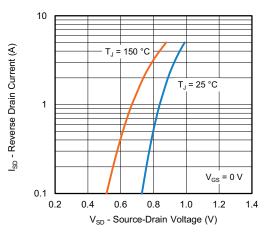


Fig. 8 - Typical Source-Drain Diode Forward Voltage

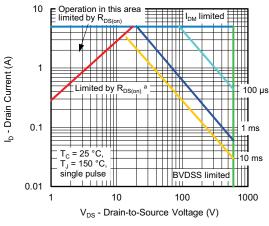


Fig. 9 - Maximum Safe Operating Area

Note

a. V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

4

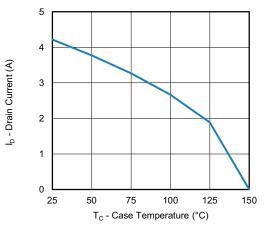


Fig. 10 - Maximum Drain Current vs. Case Temperature

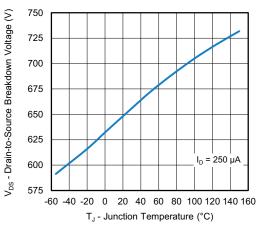
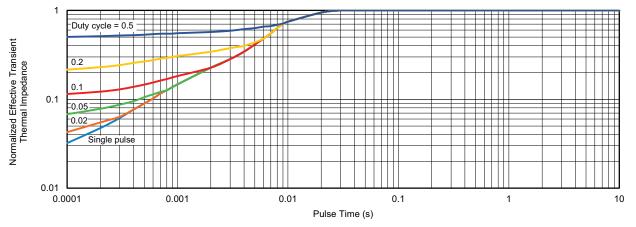


Fig. 11 - Temperature vs. Drain-to-Source Voltage



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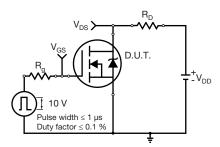


Fig. 13 - Switching Time Test Circuit

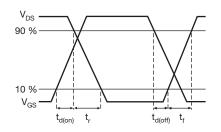


Fig. 14 - Switching Time Waveforms

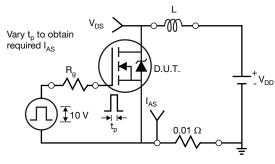


Fig. 15 - Unclamped Inductive Test Circuit

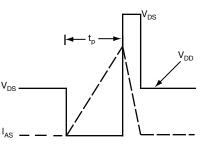


Fig. 16 - Unclamped Inductive Waveforms

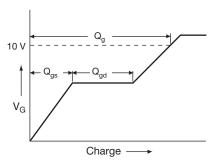


Fig. 17 - Basic Gate Charge Waveform

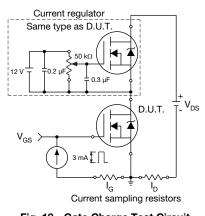


Fig. 18 - Gate Charge Test Circuit

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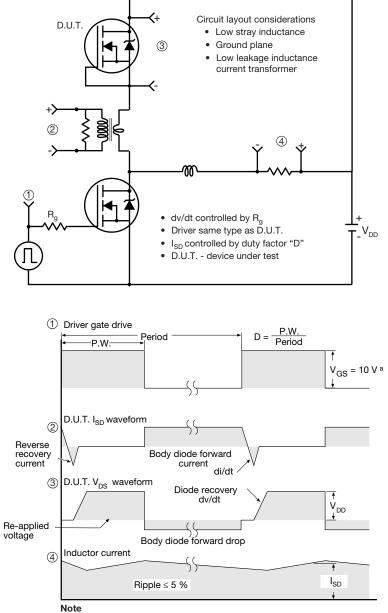
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Peak Diode Recovery dv/dt Test Circuit



a. $V_{GS} = 5$ V for logic level devices

Fig. 19 - For N-Channel

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